

# Novel Architectures for Trace Buffer Design to Facilitate Post-Silicon Validation and Test

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Thesis submitted to the Faculty of the  
Virginia Polytechnic Institute and State University  
in partial fulfillment of the requirements for the degree of

Master of Science  
in  
Computer Engineering

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April 30, 2014  
Blacksburg, Virginia

Keywords: State Restoration, Invariants, Trace Buffer Architecture  
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**Draft 09/01/2009**

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